

## Freeform Search

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<u>L5</u>	l2 and l3	1	<u>L5</u>
<u>L4</u>	l1 and l3	1	<u>L4</u>
<u>L3</u>	(window\$ near5 (mov\$ or slid\$)) and (data near5 chunk\$)	24	<u>L3</u>
<u>L2</u>	L1 and (window\$ near5 (mov\$ or slid\$))	6	<u>L2</u>
<u>L1</u>	((redundan\$ or duplicat\$) and (check\$ or test\$ or determin\$)).ab.	16982	<u>L1</u>

END OF SEARCH HISTORY

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<u>L5</u>	12 and 13	1	<u>L5</u>
<u>L4</u>	11 and 13	1	<u>L4</u>
<u>L3</u>	(window\$ near5 (mov\$ or slid\$)) and (data near5 chunk\$)	24	<u>L3</u>
<u>L2</u>	L1 and (window\$ near5 (mov\$ or slid\$))	6	<u>L2</u>
<u>L1</u>	((redundan\$ or duplicat\$) and (check\$ or test\$ or determin\$)).ab.	16982	<u>L1</u>

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IET JNL IET Journal or Magazine

IEEE CNF IEEE Conference Proceeding

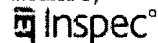
IET CNF IET Conference Proceeding

IEEE STD IEEE Standard

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